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ATTY. DOCKET N 32120.CON.1

SERIAL NO. 10/014,310

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Aro	AA	4,619	9,695	10/86	Oikawa et al		_	_		
Aio	AB	5,772	2,860	06/98	Sawada et al		_	1		
ALD	AC	5,993	3,621	11/99	Liu		1	_		
Avo	AD	5,798	8,005	08/98	Murata et al			_		
Aro	AE	5,282	2,946	02/94	Kinoshita et al		_	_		
Aro	AF	5,993	3,575	11/99	Lo et al		_	_		
ALO	AG	5,809	9,393	09/98	Dunlop et al	<i>-</i>		_		
Aro	АН	5,780	0,755	07/98	Dunlop		_			
Aro	AI	5,468	8,401	11/95	Lum					
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ATTY, DOCKET N 32120.CON.1 SERIAL NO. 10/014,310

APPLICANT Ritesh P. Shah

FILING DATE
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### U.S. PATENT DOCUMENTS

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Aro	AA	5,513,512	05/96	Segal		-	
Aro	AB	5,590,389	12/96	Dunlop	_	_	
Aro	AC	5,600,989	02/97	Segal		1	•
Aco	AD	5,673,581	10/97	Segal	~	(	<i>'</i>
ALO	AE	5,074,907	12/91	Amato et al	_	1	,
Aro	AF	4,525,417	06/85	Dimigen et al	_		
Aco	AG	4,663,120	05/87	Parent et al	_	1	·z
Aro	АН	4,762,558	08/88	German et al		(	
ALO	AI	4,889,745	12/89	Sata	_		•
Aco	AJ	5,330,701	07/94	Shaw et al		1	
Aro	AK	5,418,071	05/95	Satou et al		_	
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Aio	AA		C. Klein et a	l., "Manual o	f Mineralogy", pp 39-40	(noda	Le)		
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A16_	AC		H-R Wenk, " Texture Anal	Preferred Ori ysis", 1985, p	p 8-10 (10 mo	Metals and Rocks	: An Int	roduction	to Modern
Aro	AD		B.D. Cullity,	"Structure of	Polycrystalline Aggrega	tes", <u>Elements of</u>	X-ray I	Diffraction,	pp 294-297 <b>(100</b>
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APPLICANT Ritesh P. Shah

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#### U.S. PATENT DOCUMENTS

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Avo	AA	5,850,755	12/98	Segal		-	
Avo	- AB	5,456,815	10/95	Fukuyo et al	)		
Avo	AC	5,826,456	10/98	Kawazoe et al			
Aro	AD	5,413,650	05/95	Jarrett et al	(		
Aro	ΑE	6,193,821	2/2001	Zhang	ĺ		
Aro	AF	6,348,113	02/02	Michaluk et al	J	_	
Aco	AG	6,085,966	7/00	Shimomuki et al	(	-	
Aro	АН	6,024,852	2/00	Tamura et al		1	
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FOREIGN	PATENT DOC	UMENTS

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Aro	AM	882 813	12/1998	EPO	~	1					
Aro	AN	JP 08146201A	06/1996	Japan		_					
Aro	AO	JP 10008244A	01/1998	Japan		(					
ALO	AP	WO 9927150	06/1999	РСТ		1					
Aro	AQ	WO 9902743	01/1999	PCT	_						
ALO	AR	WO 0129279	04/2001	PCT	-	1					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

Aw	AS	Mukai, T. et al, "Dynamic Mechanical Properties of a Near-Nano Aluminum Alloy Processed by Equal-Channel-Angular-Extrusion", Nano-Structured Materials, Vol. 10, No. 5, pp. 755-765 (1998) Elsevier Science Ltd.
Dro	AT	Hatch, J.E., <u>ALUMINUM</u> , 1984, Chap. 5, "Metallurgy of Heat Treatment and General Principles of Precipitation Hardening", pp. 134-183.
Aro	AU	Ferrasse, S. et al., "Development of a Submicrometer-Grained Microstructure in Aluminum 6061 Using Equal Channel Angular Extrusion", J. Mater. Res. Vol. 12, No. 5, May 1997, pp. 1253-1261.
A <sub>1</sub> o	AV	Ferrasse, S. et al., "Microstructure and Properties of Copper and Aluminum Alloy 3003 Heavily Worked by Equal Channel Angular Extrusion", Metallurgical and Materials Transactions A, vol. 28A, April 1997, pp. 1047-1057.
Aro	AW	Pavate et al., "Correlation between Aluminum alloy sputtering target metallurgical characteristics, Arc initiation, and In-film defect density", SPIE Vol. 3214, 1997, pp. 42-47.

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Aco	AB	3,849,212	11/1974	Thornburg		148	31.55		
Aw	AC	5,766,380	06/1998	Lo et al.		148	577		
Aco	AD	6,123,896	09/2000	Meeks, III et al.		419	49		
Avo	AE	5,722,165	03/1998	Kobayashi et al.		29	894.325		
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Aro	AR	ASM Handbook,	Vol. 4, 1991, "Hea	at Treating of Aluminum Alloys",	pps. 841-879.	s Most	th data	) /	
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Aro		Materials Society,	1996, pgs. 257-262	2. (Year is sufficiently early so that the month is not an	issue.)			
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ASTM Standard Specification for Tantalum and Tantalum Alloy Plate, Sheet, and Strip, pgs. 558-561, 1992. (Year s sufficiently early so that

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ho	AR	\	Clark et al., "Influvol. 23A, pgs. 218		se Rolling on the Microstructural 192.	and Texture Developn	nent in Pure	Tantalum". N	Metallurgical T	ransactions,
to	AS	}	Raabe, et al., "Te 1994.	exture and Microst	ructure of Rolled and Annealed	Fantalum", Materials S	cience and T	echnology, V	ol. 10, pgs. 29	9-305, April
<b>A</b>	AT		Wright et al., "Te	xture Gradient El	fects in Tantalum", International	Conference on Texture	es of Materia	ls, 7 pgs., Se	ptember 1993.	
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An	AN	*			ctural Gradient Effects on the Mechanical Behavior of a Ta early so that the month is not an issue.)	ntalum Plate'	', Metallurgical	Transactions .	A, 25A	
μω										
Aro	AO		Clark et al., "Effect of Processing Variables on Texture and Texture Gradients in Tantalum", Metallurgical Transactions A, Vol. 22A, September 1991, pgs. 2039-2047).							
	<b> </b>	•	pgs. 2039-2047).		· · · · · · · · · · · · · · · · · · ·		•			
Arc	AP	•		sion Resistant Pro	operties of Tantalum" Corrosion 95, Paper No. 253, 14 page		,			
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Aw	AA	4,466,940	08/1984	Siewert et al			~				
A10	AB	4,883,721	11/1989	Nalepka		1	1				
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Aw	AD	5,623,726	04/1997	Kiiski et al		(	1				
Avo	AE	5,194,101	03/93	Worcester, et al.		~	1	- -			
ALD	AF	6,348,139	06/98	Shah							
Aro	AG	2002/0041819 A1	04/02	Kumar, et al.							
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